

Certified Reference Material

Certificate of Analysis

Product ID: IARM-FE316L-23

ISO
17034:2016

ISO/IEC
17025:2017

ISO
9001:2015

Product Description: 316L Stainless Steel, UNS S31603

Revision No.: 001
Revision Date: 09/27/2023

Description and Intended Use: This **Certified Reference Material** is covered under the scope of accreditation to **ISO 17034** by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in **ISO 17025** accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Certified Values listed in wt.% with associated uncertainties

Al	0.005	±0.002	As	0.006	±0.002	B	0.0018	±0.0004	C	0.014	±0.002
Co	0.46	±0.01	Cr	16.77	±0.09	Cu	0.300	±0.004	Mn	1.37	±0.01
Mo	2.04	±0.03	N	0.039	±0.002	Nb	0.067	±0.005	Ni	10.5	±0.1
O	0.007	±0.002	P	0.031	±0.001	S	0.024	±0.002	Si	0.226	±0.009
Sn	0.0063	±0.0005	Ti	0.0017	±0.0007	V	0.098	±0.003	W	0.103	±0.008

Indicative Values listed in ppm

Fe Balance Pb 10 Sb 14 Zr 15

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S = Standard deviation, t = t-value at 95% CI, and n = number of observations.

$$1. N_{MIN} = \max(10, \sqrt[3]{N_{PROD}}) \quad 2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognized reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- AnchorCert - Birmingham, England
- Applied Technical Services - Marietta, GA
- Avon Specialty Metals LTD - Gloucester, England
- Connecticut Metallurgical, Inc. - East Hartford, CT
- Dirats Laboratories - Westfield, MA
- Elemental Analysis Inc. - Lexington, KY
- Laboratory Testing, Inc. - Hatfield, PA
- LGC Standards - Manchester, NH
- Luvak Inc - Boylston, MA
- New Hampshire Materials Laboratory Inc - Somersworth, NH
- NSL Analytical Services - Cleveland, OH
- Scrooby's Laboratory Service Pty Ltd - Benoni, South Africa
- Sheffield Assay Office - Sheffield, England

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use.

Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Chuck Goudreau

Chuck Goudreau, Certifying Officer

September 07, 2023
Certification Date



ISO 17034 Accredited: Reference Materials
Producer, Certificate # 2848.02
ISO/IEC 17025 Accredited: Chemical
Testing, Certificate # 2848.01



Conditions of Sale and Supply: All CRMs & RMs sold are subject to applicable LGC Standard Terms and Conditions of Sale.

The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Al	As	B	C	Co	Cr	Cu	Fe	Mn	Mo	N	Nb	Ni
1	0.0020	0.0014	0.0010	0.0100	0.4237	16.34	0.2880	67.66	1.314	1.922	0.0366	0.0508	10.06
2	0.0020	0.0042	0.0010	0.0125	0.4240	16.60	0.2900	67.95	1.329	1.930	0.0370	0.0530	10.08
3	0.0037	0.0050	0.0010	0.0126	0.4380	16.60	0.2947	68.19	1.347	1.948	0.0374	0.0550	10.24
4	0.0038	0.0054	0.0012	0.0134	0.4500	16.63	0.2960		1.350	1.985	0.0380	0.0590	10.39
5	0.0040	0.0055	0.0015	0.0134	0.4537	16.63	0.2960		1.352	2.000	0.0382	0.0591	10.42
6	0.0040	0.0067	0.0017	0.0138	0.4570	16.64	0.2961		1.360	2.011	0.0392	0.0633	10.44
7	0.0056	0.0080	0.0019	0.0138	0.4576	16.72	0.2990		1.360	2.040	0.0392	0.0660	10.50
8	0.0070	0.0090	0.0019	0.0149	0.4591	16.72	0.3000		1.368	2.040	0.0420	0.0660	10.52
9	0.0090	<0.005	0.0023	0.0150	0.4600	16.80	0.3001		1.371	2.051	0.0430	0.0680	10.54
10	0.0093	<0.005	0.0023	0.0171	0.4700	16.81	0.3010		1.377	2.067		0.0680	10.59
11	0.0098	<0.005	0.0027	0.0200	0.4750	16.83	0.3029		1.377	2.070		0.0690	10.59
12	<0.001	<0.005	0.0029		0.4760	16.85	0.3060		1.380	2.070		0.0690	10.62
13	<0.002	<0.01	<0.005		0.4770	16.85	0.3070		1.385	2.071		0.0695	10.63
14	<0.005	<0.01	<0.01		0.4800	16.90	0.3090		1.387	2.075		0.0710	10.65
15	<0.005		<0.01		0.4800	16.94	0.3090		1.388	2.081		0.0768	10.68
16	<0.005				0.4830	16.95	0.3090		1.390	2.085		0.0790	10.80
17	<0.005				0.4900	16.96			1.391	2.088		0.0818	10.80
18					0.4990	17.19			1.398	2.096		0.0890	10.90
19										2.141			
Avg	0.0055	0.0057	0.0018	0.0142	0.4641	16.77	0.3002	67.93	1.368	2.041	0.0390	0.0674	10.52
SD	0.0029	0.0023	0.0007	0.0026	0.0211	0.19	0.0066	0.2656	0.023	0.060	0.0022	0.0100	0.23
Certified	0.005	0.006	0.0018	0.014	0.46	16.77	0.300	(67.9322)	1.37	2.04	0.039	0.067	10.5
Uncertainty	0.002	0.002	0.0004	0.002	0.01	0.09	0.004		0.01	0.03	0.002	0.005	0.1
Methods	I,O,G	I,O,IM	I,O,IM	C	I,X,O,G,IM	I,X,O,G	I,X,O,G,IM	X,I,O	I,X,O,G	I,X,O,G	F	I,X,O,G,IM	I,X,O,G

	O	P	Pb	S	Sb	Si	Sn	Ti	V	W	Zr
1	0.0048	0.0283	0.0010	0.0190	0.0010	0.1940	0.0050	0.0004	0.0870	0.0624	0.0004
2	0.0050	0.0289	0.0010	0.0210	0.0012	0.1947	0.0052	0.0009	0.0870	0.0750	0.0008
3	0.0051	0.0290	0.0010	0.0220	0.0013	0.2113	0.0054	0.0010	0.0900	0.0860	0.0020
4	0.0057	0.0290	<0.0001	0.0223	0.0015	0.2120	0.0060	0.0012	0.0930	0.0910	0.0020
5	0.0060	0.0290	<0.0001	0.0226	0.0021	0.2140	0.0060	0.0016	0.0950	0.0920	0.0025
6	0.0061	0.0299	<0.001	0.0232	<0.00005	0.2170	0.0060	0.0023	0.0952	0.0950	<0.0001
7	0.0095	0.0300	<0.002	0.0243	<0.0001	0.2170	0.0060	0.0024	0.0960	0.1000	<0.0005
8	0.0125	0.0300	<0.002	0.0244	<0.005	0.2180	0.0061	0.0026	0.0965	0.1005	<0.001
9		0.0304	<0.002	0.0247	<0.005	0.2252	0.0070	0.0030	0.0991	0.1006	<0.005
10		0.0307	<0.005	0.0254	<0.005	0.2300	0.0070	<0.001	0.1001	0.1020	<0.005
11		0.0307	<0.01	0.0259	<0.005	0.2300	0.0071	<0.001	0.1020	0.1030	<0.005
12		0.0310	<0.01	0.0272		0.2320	0.0075	<0.005	0.1030	0.1040	<0.005
13		0.0310		0.0300		0.2360	0.0078	<0.005	0.1032	0.1121	<0.01
14		0.0313				0.2379	<0.005	<0.005	0.1033	0.1160	<0.01
15		0.0329				0.2383	<0.01	<0.005	0.1041	0.1164	
16		0.0336				0.2490	<0.01	<0.005	0.1050	0.1170	
17		0.0340				0.2500	<0.01	<0.01	0.1100	0.1190	
18		0.0350				0.2580				0.1208	
19										0.1370	
Avg	0.0068	0.0308	0.0010	0.0240	0.0014	0.2258	0.0063	0.0017	0.0982	0.1026	0.0015
SD	0.0027	0.0019	0.0000	0.0028	0.0004	0.0178	0.0009	0.0009	0.0065	0.0174	0.0009
Certified	0.007	0.031	(0.0010)	0.024	(0.0014)	0.226	0.0063	0.0017	0.098	0.103	(0.0015)
Uncertainty	0.002	0.001		0.002		0.009	0.0005	0.0007	0.003	0.008	
Methods	F	I,X,O,G,IM	I	C,I	IM,I	I,X,O,G,IM	I,O,IM	I,X,IM,O	I,X,O,G,IM	I,X,O,G,IM	I,X

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES